

MPG Halbleiterlabor Review

Tuesday, 20 December 2016

Wafer level testing (14:00 - 16:00)

-Conveners: Johannes Treis

time	[id] title	presenter
14:00	[16] Standard Test Devices	LECHNER, Peter
14:30	[17] Device testing on wafer level	KLOSE, Daniel
15:00	[18] Flying prober	KOFFMANE, Christian
15:30	[19] PHEMOS investigations	NINKOVIC, Jelena